

Product Change Notification / JAON-13YWC0205

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16-Jul-2020

Product Category:

8-bit Microcontrollers

PCN Type:

Manufacturing Change

Notification Subject:

CCB 3600.007 Final Notice: Qualification of MMT as an additional assembly site for selected Atmel products available in 40L PDIP package.

Affected CPNs:

JAON-13YWCO205_Affected_CPN_07162020.pdf JAON-13YWCO205_Affected_CPN_07162020.csv

Notification Text:

PCN Status: Final notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change: Qualification of MMT as an additional assembly site for selected Atmel products available in 40L PDIP package.

Pre Change:

Assembled at LPI assembly site using palladium coated copper with gold flash (CuPdAu) bond wire, CRM-1033BF die attach and G600 mold compound material or assembled at ASSH using palladium coated copper (PdCu) bond wire, EN-4900G die attach and CEL-9240 mold compound material.

Post Change:

Assembled at ASSH using palladium coated copper (PdCu) bond wire, EN-4900G die attach and CEL-9240 mold compound material or assembled at MMT assembly site using palladium coated copper with gold flash (CuPdAu) bond wire, CRM-1064L die attach and GE800 mold compound material.

Pre and Post Change Summary:

	Pre Chan	ge	Post Change			
Assembly Site	Lingsen Precision Industries, Taiwan (LPI)	ASE-Shanghai (ASSH)	ASE-Shanghai (ASSH)	Microchip Technology Thailand (Branch) - (MMT)		
Wire material	CuPdAu	PdCu	PdCu	CuPdAu		
Die attach material	CRM-1033BF	EN-4900G	EN-4900G	CRM-1064L		
Molding compound material	G600	CEL-9240	CEL-9240	GE800		
Lead frame material	CDA194	CDA194	CDA194	CDA194		

Impacts to Data Sheet: None

Change Impact:None

Reason for Change:To improve on time delivery performance by qualifying MMT as an additional assembly site. Due to unforeseen business conditions the LPI location will be discontinued as an assembly site for 40L PDIP package.

Change Implementation Status:In Progress

Estimated First Ship Date: August 15, 2020 (date code: 2033)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	July 2020			August 2020						
Workweek	27	28	29	30	31	32	33	34	35	36
Qual Report Availability			Χ							
Final PCN Issue Date			Х							
Estimated Implementation Date							Χ			

Method to Identify Change: Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual Report.

Revision History:July 16, 2020: Issued final notification. Attached the qualification report. Provided estimated first ship date to be on August 15, 2020.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

PCN_JAON-13YWCO205_Qual_Report.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

AT89LS51-16PU AT89S51-24PU

AT89LS52-16PU

AT89S52-24PU

Date: Thursday, July 16, 2020



QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN #: JAON-13YWCO205

Date: October 28, 2019

Qualification of MMT as an additional assembly site for selected Atmel products available in 40L PDIP package.



Purpose Qualification of MMT as an additional assembly site for selected Atmel products

available in 40L PDIP package.

CN ES303598

QUAL ID Q19095 rev A

MP CODE 354527S2XA01

Part No. ATMEGA1284P-PU Bonding No. BDM-001967 Rev. A

CCB No. 3600, 3600.001, 3600.002, 3600.003, 3600.004, 3600.005, 3600.006 and 3600.007

Package

Type 40L PDIP Package size 600 mils

Lead Frame

Paddle size 260 x 266 mils

Material CDA194

Surface Ag Spot Plated

Process Stamped

Lead Lock Yes

Part Number 10104004

Die attach material

Epoxy CRM-1064L Wire CuPdAu wire

Mold Compound GE800
Plating Composition Matte Tin



Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MMT-201101010.000	MCSO519496553.210	1924EPS
MMT-201101013.000	MCSO519496553.210	1924ERS
MMT-201101391.000	MCSO519496553.210	1924H10

Result	X Pass	Fail		
	401 PDIP (600") asse	mbled by MM7	T nass reliability test ner C	CI-39000

PACKAGE QUALIFICATION REPORT							
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks	
Electrical Test	Electrical Test:+25°C and 85°C System: J750	JESD22- A113	693(0)	693		Good Devices	
	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Inspection: External crack inspection all units under 40X Optical magnification	JESD22- A104		231			
	Electrical Test: +85°C System: MAV1_PT		231(0)	0/231	Pass	77 units / lot	
Temp Cycle	Stress Condition: -65°C to +150°C, 1000 Cycles System: TABAI ESPEC TSA-70H Inspection: External crack inspection all units under 40X Optical magnification			231			
	Electrical Test: +85°C System: MAV1_PT		231(0)	0/231	Pass		
	Bond Strength: Wire Pull (> 2.50 grams)		15 (0)	0/15	Pass		
	Bond Shear (15.00 grams)		15 (0)	0/15	Pass		
	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		231			
UNBIASED-HAST	Electrical Test: +85°C System: MAV1_PT		231(0)	0/231	Pass	77 units / lot	
	Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X			231			
	Electrical Test: +85°C System: MAV1_PT		231(0)	0/231	Pass		

	PACKAGE QUALIFICA	ATION	REP	ORT		
Test Number	Test Condition	Standard/	Qty.	Def/SS.	Result	Remarks
(Reference)		Method	(Acc.)			
	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 5.5 Volts System: HAST 6000X	JESD22- A110		231		
	Electrical Test: +85°C System: MAV1_PT		231(0)	0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 192 hrs. Bias Volt: 5.5 Volts System: HAST 6000X			231		
	Electrical Test: +85°C System: MAV1_PT		231(0)	0/231	Pass	
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22- A103		45		45 units
Storage Life	Electrical Test: +85°C System: MAV1_PT		45(0)	0/45	Pass	
Bond Strength	Wire Pull (> 2.50 grams)	M2011	30 (0) Wires	0/30	Pass	
Data Assembly	Bond Shear (15.00 grams)	JESD22- B116	30 (0) bonds	0/30	Pass	